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Data Sheet

August 13, 2026

YOKOGAWA

Yokogawa AQ6375E 1200-2400nm Optical Spectrum Analyzer

Yokogawa AQ6375E Optical Spectrum Analyzer The Yokogawa AQ6375E is a diffraction-grating benchtop optical spectrum analyzer covering 1200 to 2400 nm (1000 to 2500 nm extended option) for WDM, component, and research photonics spectral measurement. Built-in analysis for WDM, OSNR, EDFA NF, laser SMSR, and related telecom/photonics tests. WDM channel and OSNR analysis; EDFA gain and noise figure; DFB/FP/LED spectral characterization; visible-to-IR component test; R&D and production optical spectrum verification. The Yokogawa AQ6375E is a diffraction-grating benchtop optical spectrum analyzer covering 1200 to 2400 nm (1000 to 2500 nm extended option) for WDM, component, and research photonics spectral measurement. Built-in analysis for WDM, OSNR, EDFA NF, laser SMSR, and related telecom/photonics tests. WDM channel and OSNR analysis; EDFA gain and noise figure; DFB/FP/LED spectral characterization; visible-to-IR component test; R&D and production optical spectrum verification.



MODEL

**Yokogawa
AQ6375E**

CALIBRATION

**Available on
request**

CONDITION

Used

STATUS

In stock

RFQ / SKU

AQ6375E

LISTING

<https://aumictechlabs.com/products/aq6375e-2/>

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 · 811210 · 541380

This unit

The Yokogawa AQ6375E is a optical spectrum analyzer delivering precise spectral measurements across the 1200–2400 nm wavelength range. Engineered for telecommunications, optical device characterization, and production environments, it combines superior resolution, extended dynamic range, and rapid sweep capability to provide detailed analysis of optical signals in the extended near-infrared spectrum. The instrument measures spectral amplitude from –70 dBm to +20 dBm with ± 0.5 dB accuracy at 1550 nm, achieving more than 50 dB dynamic range at 0.1 nm resolution. Its selectable resolution bandwidths span 0.05 nm to 10 nm, supporting wavelength accuracy of ± 0.1 nm (1500–1700 nm) and ± 0.2 nm (1200–1500 nm, 1700–2400 nm). With minimum sweep times of 0.2 seconds over 50 nm ranges and full-featured analysis functions, the AQ6375E enables rapid characterization of lasers, optical amplifiers, filters, and passive components.

Technical Specifications

Wavelength Range:	1200 nm to 2400 nm
Wavelength Accuracy:	± 0.1 nm (1500–1700 nm); ± 0.2 nm (1200–1500 nm, 1700–2400 nm)
Wavelength Resolution:	0.05 nm minimum (typical); selectable 0.05 nm to 10 nm
Level Measurement Range:	–70 dBm to +20 dBm
Level Accuracy:	± 0.5 dB @ 1550 nm
Dynamic Range:	>50 dB (peak to noise floor @ 1550 nm, 0.1 nm resolution)
Optical Input:	FC/APC connector; +23 dBm maximum input power
Minimum Sweep Time:	0.2 seconds (50 nm range)
Dimensions:	425 mm (W) × 195 mm (H) × 450 mm (D)
Weight:	22 kg (approx.)
Power Supply:	100–240 VAC, 50/60 Hz; 300 VA maximum

Key Features Peak search, level measurement, and wavelength measurement functions
Spectrum averaging and noise level measurement
Threshold setting and pass/fail testing capability
Color LCD wavelength vs. level display
External trigger and reference clock inputs/outputs

Typical Applications WDM system laser and optical amplifier characterization
Spectral purity and side-mode suppression ratio (SMSR) analysis
Optical filter, grating, and passive component spectral measurement
Extended near-infrared device testing and validation

Compatibility & Integration USB 2.0 (Type A and Mini-B) for data transfer and instrument control
Ethernet 10/100/1000 Base-T for remote access
GPIB (IEEE 488.2) for remote control

Features & description

From manufacturer datasheet

Features

- Wavelength range 1200 to 2400 nm (1000 to 2500 nm extended option)

Polarization Dependence: +/-0.15 dB typical (1550 nm class)

Warm Up Time: minimum 1 hour Applicable Fiber: SM (9/125); MM (50/125, 62.5/125); large core to 800 um (model dependent) Optical Connector: FC or SC via adapter (option) Built in Reference Source: wavelength reference for alignment and calibration Alias: AQ6375E Span Range: per AQ6375E datasheet Level Accuracy: per AQ6375E datasheet Purge Feature: available for SWIR measurement stability Dimensions: approx. 426 W x 177 H x 459 D mm Mass: approx. 14 kg Operating Temperature: +10 to +30 degCperformance guarantee Notes Specs from Yokogawa AQ6375E datasheet and OSA selection guide. SWIR 2 um class; purge feature available. Confirm installed suffix (-10 Standard, -20 High Performance where applicable).

AQ6375E Characteristics / Specifications

PARAMETER	VALUE
Model	AQ6375E
Manufacturer	Yokogawa
Instrument Type	Optical Spectrum Analyzer
Wavelength Range	1200 to 2400 nm (1000 to 2500 nm extended option)
Wavelength Accuracy	+/-0.05 nm (1520 to 1580 nm); +/-0.5 nm (overall)
Resolution Settings	0.05 to 2 nm
Level Range	+20 to -70 dBm
Level Sensitivity	-70 dBm (1400 to 1600 nm)
Close in Dynamic Range	45 dB (+/-0.4 nm)
Input	Free-space; SM, MM, and large-core fiber compatible
Analysis Functions	WDM, OSNR, EDFA NF, DFB/FP/LED, SMSR, color analysis (visible models)
Sweep Speed	per AQ6375E datasheet
Max Safe Input Power	+20 dBm class (wavelength dependent)
Polarization Dependence	+/-0.15 dB typical (1550 nm class)
Warm Up Time	minimum 1 hour
Applicable Fiber	SM (9/125); MM (50/125, 62.5/125); large core to 800 um (model dependent)
Optical Connector	FC or SC via adapter (option)
Built in Reference Source	wavelength reference for alignment and calibration
Alias	AQ6375E
Span Range	per AQ6375E datasheet
Level Accuracy	per AQ6375E datasheet
Purge Feature	available for SWIR measurement stability
Dimensions	approx. 426 W x 177 H x 459 D mm
Mass	approx. 14 kg

PARAMETER	VALUE
Operating Temperature	+10 to +30 degCperformance guarantee Notes Specs from Yokogawa AQ6375E datasheet and OSA selection guide. SWIR 2 um class; purge feature available. Confirm installed suffix (-10 Standard, -20 High Performance where applicable).

General Specifications & Supplementary Characteristics

PARAMETER	VALUE
Operating temperature	+10 to +30 degCperformance guarantee
Operating Temperature	+10 to +30 degCperformance guarantee

Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

Specifications	
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PARAMETER	VALUE
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Specifications

PARAMETER	VALUE
Alias	AQ6375E
Span Range	per AQ6375E datasheet
Level Accuracy	per AQ6375E datasheet

Specifications

PARAMETER	VALUE
Purge Feature	available for SWIR measurement stability
Dimensions	approx. 426 W x 177 H x 459 D mm
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Notes

Specs from Yokogawa AQ6375E datasheet and OSA selection guide. SWIR 2 um class; purge feature available. Confirm installed suffix (-10 Standard, -20 High Performance where applicable).

Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: sales@aumictech.com · +1 (484) 841-9341

Aumictech

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<https://aumictechlabs.com>

NIST-traceable calibration · SAM registered ·
30-day returns
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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.